Paper Citation

26.05.2021

Published: 2013

A Digitally Programmable A/D Converter for Smart Sensors

IEEE Transactions on Instrumentation and Measurement

Published: 2007

Show More

Abstract

Document Sections

PDF

1 Introduction

Description

3 Experimental

Results

2 System

Abstract: This paper dedicates a particular attention to pulse-width modulation (PWM) analog-to-digital (A/D) conversion techniques underlining their importance in smart sensing s... View more

Metadata

4 Conclusion

Authors

Figures

References

Citations Keywords

Metrics

More Like This

Abstract: This paper dedicates a particular attention to pulse-width modulation (PWM) analog-todigital (A/D) conversion techniques underlining their importance in smart sensing systems. Nowadays, smart sensing systems and advanced signal processing techniques can improve measuring system's performance and flexibility relaxing hardware specifications and associated cost. The integration of sensing units, conditioning circuitry and A/D conversion is becoming trivial in a large number of instrumentation and measurement applications. In a large number of systems, linearization is generally required because most sensors have an intrinsic nonlinear characteristic or the presence of influence variables makes their characteristic nonlinear over its measuring range. Fortunately, digitalization and linearization can be performed in a single step nearby the transducer in smart sensing systems, A possible solution to achieve this goal is based on a PWM scheme for nonlinear A/D conversion. The proposed A/D conversion method is easily implemented in low-cost microcontrollers that generally include comparator inputs and PWM outputs. The input voltage range can be divided in several intervals and the nonlinearity profile of the A/D in each interval can be dynamically adapted if results from calibration or auto-calibration are available even when hysteresis effects are present. The paper includes some simulation results obtained with MATLAB and an experimental result of a strain gage system linearization is also presented in the final part of the paper.

Published in: 2007 8th International Conference on Electronic Measurement and Instruments

Date of Conference: 16-18 Aug. 2007 **INSPEC Accession Number: 9717308**

Date Added to IEEE Xplore: 22 October

2007

ISBN Information:

DOI: 10.1109/ICEMI.2007.4350496

Publisher: IFFF

Conference Location: Xi'an, China

Contents

1 Introduction

An ideal device or system is one for which cause and effect are proportional. The linearity conducts to linear characteristics, i.e., a constant sensitivity of the measurement system over its measuring

range. However, all devices particularly sensors are nonlinear even when a restricted measuring range is considered. Much design effort is dedicated in finding and using devices with exceptional linearity, and in the development of conditioning and normalizing circuits to match or compensate nonlinear effects that are always present [1].

Authors	~
Figures	~
References	~
Citations	~
Keywords	~
Metrics	~

IEEE Personal Account CHANGE USERNAME/PASSWORD **Purchase Details** PAYMENT OPTIONS

VIEW PURCHASED DOCUMENTS

Profile Information

COMMUNICATIONS PREFERENCES PROFESSION AND EDUCATION

TECHNICAL INTERESTS

Need Help?

US & CANADA: +1 800 678 4333

WORLDWIDE: +1 732 981 0060

CONTACT & SUPPORT





About IEEE Xplore | Contact Us | Help | Accessibility | Terms of Use | Nondiscrimination Policy | Sitemap | Privacy & Opting Out of Cookies

A not-for-profit organization, IEEE is the world's largest technical professional organization dedicated to advancing technology for the benefit of humanity.

© Copyright 2021 IEEE - All rights reserved. Use of this web site signifies your agreement to the terms and conditions

IEEE Account

- » Change Username/Password
- » Update Address

Purchase Details

- » Payment Options
- » Order History
- » View Purchased Documents

Profile Information

- » Communications Preferences
- » Profession and Education
- » Technical Interests

Need Help?

- » US & Canada: +1 800 678 4333
- » Worldwide: +1 732 981 0060
- » Contact & Support

About IEEE Xplore | Contact Us | Help | Accessibility | Terms of Use | Nondiscrimination Policy | Sitemap | Privacy & Opting Out of Cookies

A not-for-profit organization, IEEE is the world's largest technical professional organization dedicated to advancing technology for the benefit of humanity. © Copyright 2021 IEEE - All rights reserved. Use of this web site signifies your agreement to the terms and conditions.